







SN65ALS176, SN75ALS176 **SN75ALS176A, SN75ALS176B**

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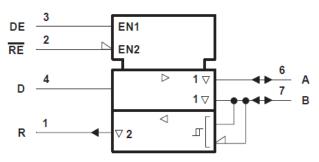
SNx5ALS176, SN75ALS176A, and SN75ALS176B Differential Bus Transceivers

1 Features

- Meet or exceed the requirements of TIA/EIA-422-B,TIA/EIA-485-A¹ and ITU recommendations V.11 and X.27
- Operate at data rates up to 35 Mbaud
- Four skew limits available:
 - SN65ALS176: 15 ns
 - SN75ALS176: 10 ns
 - SN75ALS176A: 7.5 ns
 - SN75ALS176B: 5 ns
- Designed for multipoint transmission onlong bus lines in noisy environments
- Low supply-current requirements: 30 mA max
- Wide positive and negative input/output busvoltage ranges
- Thermal shutdown protection
- Driver positive and negative current limiting
- Receiver input hysteresis
- Glitch-free power-up and power-down protection
- Receiver open-circuit fail-safe design

2 Description

The SN65ALS176 and **SN75ALS176** differential bus transceivers are designed for bidirectional data communication on multipoint bus transmission lines. The devices are designed for balanced transmission lines and meet TIA/EIA-422-B, TIA/EIA-485-A, and ITU Recommendations V.11 and X.27.



This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Logic Symbol

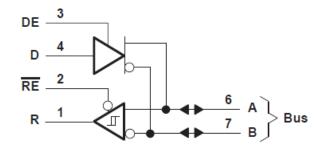
The SN65ALS176 and SN75ALS176 series combine a 3-state, differential line driver and a differential input line receiver, both of which operate from a single 5-V power supply. The driver and receiver have activehigh and active-low enables, respectively, that can be connected together externally to function as a direction control. The driver differential outputs and the receiver differential inputs are connected internally to form a differential input/output (I/O) bus port that is designed to offer minimum loading to the bus when the driver is disabled or V_{CC} = 0. This port features wide positive and negative common-mode voltage ranges, making the device suitable for partyline applications.

The SN65ALS176 is characterized for operation from -40°C to 85°C. The SN75ALS176 series is characterized for operation from 0°C to 70°C.

Package Information

i dokago ililorillation							
PACKAGE ⁽¹⁾	BODY SIZE (NOM)						
D (SOIC)	4.9 mm x 3.91 mm						
P (PDIP)	9.81 mm x 6.35 mm						
D (SOIC)	4.9 mm x 3.91 mm						
P (PDIP)	9.81 mm x 6.35 mm						
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P (PDIP)	9.81 mm x 6.35 mm						
	PACKAGE ⁽¹⁾ D (SOIC) P (PDIP) D (SOIC) P (PDIP) D (SOIC)						

For all available packages, see the orderable addendum at the end of the data sheet.



Logic Diagram (Positive Logic)

¹ These devices meet or exceed the requirements of TIA/EIA-485-A, except for the Generator Contention Test (para. 3.4.2) and the Generator Current Limit (para. 3.4.3). The applied test voltage ranges are -6 V to 8 V for the SN75ALS176, SN75ALS176A, and SN75ALS176B and -4 V to 8 V for the SN65ALS180.



Table of Contents

1 Features1	6 Parameter Measurement Information11
2 Description1	7 Detailed Description14
3 Revision History2	7.1 Functional Block Diagram14
4 Pin Configuration and Functions3	7.2 Device Functional Modes14
5 Specifications4	8 Application and Implementation15
5.1 Absolute Maximum Ratings4	8.1 Application Information15
5.2 Recommended Operating Conditions4	8.2 Typical Application15
5.3 Thermal Information4	9 Device and Documentation Support16
5.4 Electrical Characteristics - Driver5	9.1 Documentation Support16
5.5 Switching Characteristics - Driver5	9.2 Receiving Notification of Documentation Updates16
5.6 Switching Characteristics - Driver6	9.3 Support Resources16
5.7 Symbol Equivalents6	9.4 Trademarks16
5.8 Electrical Characteristics - Receiver	9.5 Electrostatic Discharge Caution16
5.9 Switching Characteristics - Receiver	9.6 Glossary16
5.10 Switching Characteristics - Receiver8	10 Mechanical, Packaging, and Orderable
5.11 Typical Characteristics9	Information16

3 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Page
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4 Pin Configuration and Functions

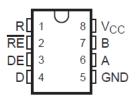


Figure 4-1. D or P Package (Top View)

Table 4-1. Pin Functions

NO	Name	Туре	Description
1	R	0	Receive data output
2	RE	I	Receiver enable, active low
3	DE	i	Driver enable, active high
4	D	1	Driver data input
5	GND	GND	Local device ground
6	Α	I/O	Driver output or receiver input (complementary to B)
7	В	I/O	Driver output or receiver input (complementary to A)
8	V _{CC}	SUPPLY	4.75-V to 5.25-V supply



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
V _{CC}	Supply voltage ⁽²⁾		7	V
	Voltage range at any bus terminal	-7	12	V
VI	Enable input voltage		5.5	V
	Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds		260	°C
T _{stg}	Storage temperature range	-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions

(unless otherwise noted)

			MIN	NOM	MAX	UNIT	
V _{CC}	Supply voltage		4.75	5	5.25	V	
				12	V		
V _I or V _{IC}	imput voltage at any bus terminal (sep	Input voltage at any bus terminal (separately or common mode)			-7	V	
V _{IH}	High-level input voltage	D, DE, and RE	2			V	
V _{IL}	Low-level input voltage	D, DE, and RE			0.8	V	
V _{ID}	Differential input voltage ⁽¹⁾			±12	V		
	High-level output current	Driver			-60	mA	
Іон	High-level output current	Receiver			-400	μA	
	Low-level output current	Driver			60	mA	
l _{OL}	Low-level output current	Receiver			8	ША	
т	Operating free-air temperature	SN65ALS176	-40		85	°C	
T_A	Operating nee-all temperature	SN75ALS176 series	0		70		

⁽¹⁾ Differential input/output bus voltage is measured at the noninverting terminal A with respect to the inverting terminal B.

5.3 Thermal Information

		P (PDIP)	D (SOIC) SN65 Devices	D (SOIC) SN75 Devices	
THERMAL METRIC ⁽¹⁾		8-Pins	8-Pins	8-Pin	UNIT
R _{θJA}	Junction-to-ambient thermal resistance	65.7	116.7	110	°C/W
R _{θJC(top)}	Junction-to-case thermal resistance	54.7	56.3	44.1	°C/W
R _{θJB}	Junction-to-board thermal resistance	42.1	63.4	53.5	°C/W
Ψ ЈТ	Junction-to-top characterization parameter	23	8.8	4.8	°C/W
Ψ ЈВ	Junction-to-board characterization parameter	41.7	62.6	52.7	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	N/A	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

⁽²⁾ All voltage values, except differential I/O bus voltage, are with respect to network ground terminal.



5.4 Electrical Characteristics - Driver

over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS(1)		MIN	TYP ⁽²⁾	MAX	UNIT
V _{IK}	Input clamp voltage	I _I = -18 mA				-1.5	V
Vo	Output voltage	I _O = 0		0		6	V
l _{OD1} l	Differential output voltage	I _O = 0		1.5		6	V
V _{OD2}	Differential output voltage	R _L = 100 Ω	See Figure 6-1	½ V _{OD1} or 2 ⁽³⁾			V
	, ,	R _L = 54 Ω	See Figure 6-1	1.5	2.5	5	V
V _{OD3}	Differential output voltage	$V_{\text{test}} = -7 \text{ V to } 12 \text{ V},$	See Figure 6-2	1.5		5	V
$\Delta V_{OD} $	Change in magnitude of differential output voltage ⁽⁴⁾	R_L = 54 Ω or 100 Ω	See Figure 6-1			±0.2	V
V _{OC}	Common-mode output voltage	R_L = 54 Ω or 100 Ω	See Figure 6-1			3 –1	V
Δ V _{OC}	Change in magnitude of common-mode output voltage ⁽⁴⁾	R_L = 54 Ω or 100 Ω	See Figure 6-1			±0.2	V
	Outrout summent	Outputs disabled ⁽⁶⁾	V _O = 12 V			1	mA
lo	Output current	Outputs disabled	V _O = -7 V			-0.8	ША
I _{IH}	High-level input current	V _I = 2.4 V				20	μΑ
I _{IL}	Low-level input current	V _I = 0.4 V				-400	μΑ
		V _O = -4 V	SN65ALS176			-250	
		V _O = -6 V	SN75ALS176			-250	
Ios	Short-circuit output current ⁽⁵⁾	V _O = 0				-150	mA
		V _O = V _{CC}				250	
		V _O = 8 V				250	
1	Supply current	No load	Outputs enabled		23	30	mA
I _{CC}	опрріу сипені	INO IOAU	Outputs disabled		19	26	шА

- (1) The power-off measurement in TIA/EIA-422-B applies to disabled outputs only and is not applied to combined inputs and outputs.
- (2) All typical values are at V_{CC} = 5 V and T_A = 25°C.
- (3) The minimum V_{OD2} with a 100- Ω loadis either 1/2 V_{OD1} or 2 V, whichever is greater.
- (4) Δ|V_{OD}| and Δ|V_{OC}| are the changes in magnitude of VOD and VOC, respectively, that occur when the input is changed from one logic state to the other.
- (5) Duration of the short circuit should not exceed one second for this test.
- (6) This applies for power on and power off. Refer to TIA/EIA-485-A for exact conditions. The TIA/EIA-422-B limit does not apply for a combined driver and receiver terminal.

5.5 Switching Characteristics - Driver

SN65ALS176

over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS			MIN	TYP ⁽¹⁾	MAX	UNIT
t _{d(OD)}	Differential output delay time	R _L = 54 Ω	C _L = 50 pF,	See Figure 6-3			15	ns
t _{sk(p)}	Pulse skew ⁽²⁾	R _L = 54 Ω	C _L = 50 pF,	See Figure 6-3		0	2	ns
t _{sk(lim)}	Pulse skew ⁽³⁾	R _L = 54 Ω	C _L = 50 pF,	See Figure 6-3			15	ns
t _{t(OD)}	Differential output transition time	R _L = 54 Ω	C _L = 50 pF,	See Figure 6-3		8		ns
t _{PZH}	Output enable time to high level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-4			80	ns
t _{PZL}	Output enable time to low level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-5			30	ns
t _{PHZ}	Output disable time from high level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-4			50	ns
t _{PLZ}	Output disable time from low level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-5			30	ns

(1) All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



- Pulse skew is defined as the $|t_{\text{PLH}}\!\!-\!t_{\text{PHL}}|$ of each channel of the same device.
- Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.

5.6 Switching Characteristics - Driver

SN75ALS176, SN75ALS176A, SN75ALS176B

over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

	PARAMETER			TEST CONDITIONS			TYP ⁽¹⁾	MAX	UNIT
	D. 155	'ALS176				3	8	13	
t _{d(OD)}	Differential output delay time	'ALS176A	$R_L = 54 \Omega$	$C_L = 50 \text{ pF},$	See Figure 6-3	4	7	11.5	ns
	acia, iiiic	'ALS176B				5	8	10	
t _{sk(p)}	Pulse skew ⁽²⁾		R _L = 54 Ω	C _L = 50 pF,	See Figure 6-3		0	2	ns
		'ALS176						10	
t _{sk(lim)}	Pulse skew ⁽³⁾	'ALS176A	R _L = 54 Ω	C _L = 50 pF,	See Figure 6-3			7.5	ns
		'ALS176B						5	
t _{t(OD)}	Differential output tra	nsition time	R _L = 54 Ω	C _L = 50 pF,	See Figure 6-3		8		ns
t _{PZH}	Output enable time to	high level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-4		23	50	ns
t _{PZL}	Output enable time to	low level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-5		14	20	ns
t _{PHZ}	Output disable time f	rom high level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-4		20	35	ns
t _{PLZ}	Output disable time f	rom low level	R _L = 110 Ω	C _L = 50 pF,	See Figure 6-5		8	17	ns

- (1)
- All typical values are at V_{CC} = 5 V, T_A = 25°C. Pulse skew is defined as the $|t_{PLH}-t_{PHL}|$ of each channel of the same device.
- Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.

5.7 Symbol Equivalents

DATA-SHEET PARAMETER	TIA/EIA-422-B	TIA/EIA-485-A
Vo	V _{oa} , V _{ob}	V _{oa} , V _{ob}
V _{OD1}	V _o	V _o
V _{OD2}	V _t (R _L = 100 Ω)	V _t (R _L = 54 W)
V _{OD3}	None	V _t (test termination measurement 2)
Δ V _{OD}	$ V_t - V_t $	$ V_t - V_t $
V _{oc}	V _{os}	V _{os}
Δ V _{OC}	V _{os} - V _{os}	V _{os} -V _{os}
I _{os}	I _{sa} , I _{sb}	None
Io	Ix _a , I _{xb}	I _{ia} , I _{ib}



5.8 Electrical Characteristics - Receiver

over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST COM	IDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IT+}	Positive-going input threshold voltage	V _O = 2.7 V,	I _O = -0.4 mA			0.2	V
V _{IT} -	Negative-going input threshold voltage	V _O = 0.5 V,	I _O = 8 mA	-0.2 ⁽²⁾			V
V _{hys}	Hysteresis voltage (V _{IT+} – V _{IT-})				60		mV
V _{IK}	Enable-input clamp voltage	I _I = -18 mA				-1.5	V
V _{OH}	High-level output voltage	V _{ID} = 200 mV, See Figure 6-6	I _{OH} = -400 mA,	2.7			V
V _{OL}	Low-level output voltage	V _{ID} = -200 mV, SeeFigure 6	I _{OL} = 8 mA,			0.45	V
I _{OZ}	High-impedance-state output current	V _O = 0.4 V to 2.4 V				±20	μA
\/	Line input current	011 : 1 0 1 (3)	V _I = 12 V			1	A
VI	Line input current	Other input = 0 V ⁽³⁾	V _I = -7 V			-0.8	mA
I _{IH}	High-level-enable input current	V _{IH} = 2.7 V				20	μΑ
I _{IL}	Low-level-enable input current	V _{IL} = 0.4 V				-100	μΑ
r _l	Input resistance			12	20		kΩ
I _{OS}	Short-circuit output current	V _{ID} = 200 mV,	V _O = 0	-15		-85	mA
	Cumply surrent	No lood	Outputs enabled		23	30	A
I _{CC}	Supply current	No load	Outputs disabled		19	26	mA

⁽¹⁾ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

5.9 Switching Characteristics - Receiver

SN65ALS176

over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONE	MIN	TYP ⁽¹⁾	MAX	UNIT	
t _{pd}	Propagation time	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V,}$ See Figure 6-7	C _L = 15 pF,			25	ns
t _{sk(p)}	Pulse skew ⁽²⁾	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V,}$ See Figure 6-7	C _L = 15 pF,		0	2	ns
t _{sk(lim)}	Pulse skew ⁽³⁾	$R_L = 54 \Omega$ See Figure 6-3	C _L = 50 pF,			15	ns
t _{PZH}	Output enable time to high level	C _L = 15 pF,	See Figure 6-8		11	18	ns
t _{PZL}	Output enable time to low level	C _L = 15 pF,	See Figure 6-8		11	18	ns
t _{PHZ}	Output disable time from high level	C _L = 15 pF,	See Figure 6-8			50	ns
t _{PLZ}	Output disable time from low level	C _L = 15 pF,	See Figure 6-8			30	ns

⁽¹⁾ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for common-mode input voltage and threshold voltage levels only.

⁽³⁾ This applies for power on and power off. Refer to TIA/EIA-485-A for exact conditions.

⁽²⁾ Pulse skew is defined as the $|t_{PLH}-t_{PHL}|$ of each channel of the same device.

⁽³⁾ Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.

5.10 Switching Characteristics - Receiver

SN75ALS176,SN75ALS176A, SN75ALS176B

over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONI	TEST CONDITIONS			MAX	UNIT
		'ALS176	V 45V4-45V		9	14	19	
t _{pd}	Propagation time	'ALS176A	V _{ID} = -1.5 V to 1.5 V, See Figure 6-7	C _L = 15 pF,	10.5	14	18	ns
		'ALS176B			11.5	13	16.5	
t _{sk(p)}	Pulse skew ⁽²⁾		$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V},$ See Figure 6-7	C _L = 15 pF,		0	2	ns
		'ALS176	D 540				10	
t _{sk(lim)}	Pulse skew ⁽³⁾	'ALS176A	R_L = 54 Ω See Figure 6-3	$C_L = 50 \text{ pF},$			7.5	ns
		'ALS176B	See rigule 0-3				5	
t _{PZH}	Output enable time to h	igh level	C _L = 15 pF,	See Figure 6-8		7	14	ns
t _{PZL}	Output enable time to low level		C _L = 15 pF,	See Figure 6-8		20	35	ns
t _{PHZ}	Output disable time from high level		C _L = 15 pF,	See Figure 6-8		20	35	ns
t _{PLZ}	Output disable time from	n low level	C _L = 15 pF,	See Figure 6-8		8	17	ns

 ⁽¹⁾ All typical values are at V_{CC} = 5 V, T_A = 25°C.
 (2) Pulse skew is defined as the |t_{PLH}-t_{PHL}| of each channel of the same device.

Skew limit is the maximum difference in propagation delay times between any two channels of any two devices.



5.11 Typical Characteristics

Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

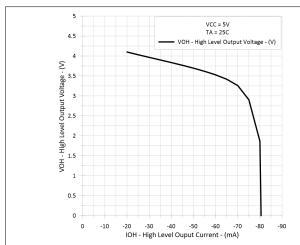


Figure 5-1. Driver High-LeveL Output Voltage vs High-Level Output Current

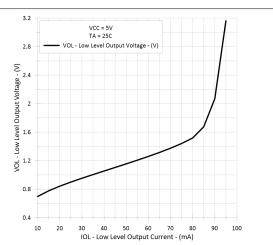


Figure 5-2. Driver Low-Level Output Voltage vs Low-Level Output Current

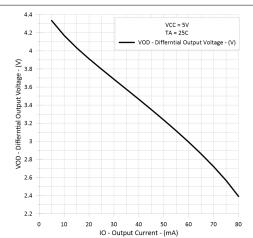


Figure 5-3. Driver Differential Output Voltage vs Output Current

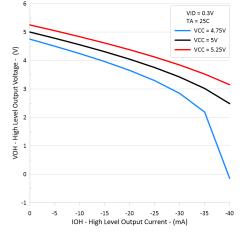


Figure 5-4. Receiver High-Level Output Voltage vs High-Level Output Current

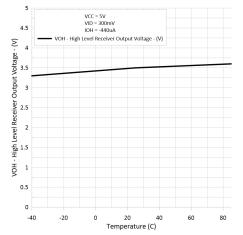


Figure 5-5. Receiver High-Level Output Voltage vs Free-Air Temperature

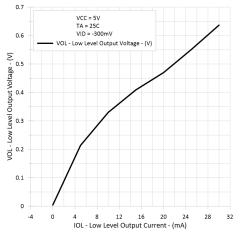
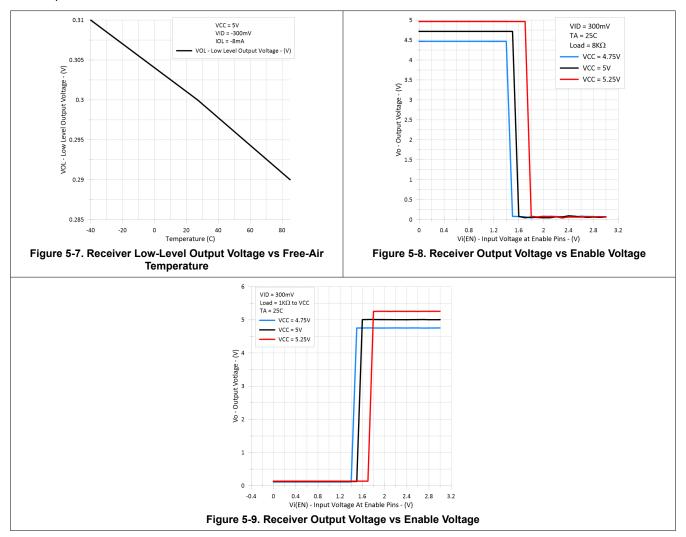


Figure 5-6. Receiver Low-Level Output Voltage vs Low-Level Output Current



5.11 Typical Characteristics (continued)

Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.





6 Parameter Measurement Information

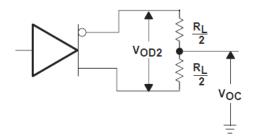


Figure 6-1. Driver V_{OD2} and V_{OC}

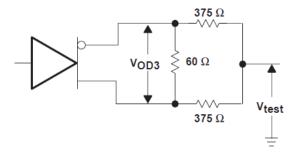
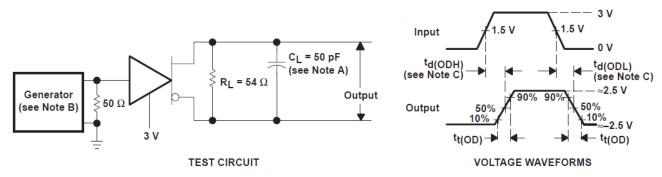
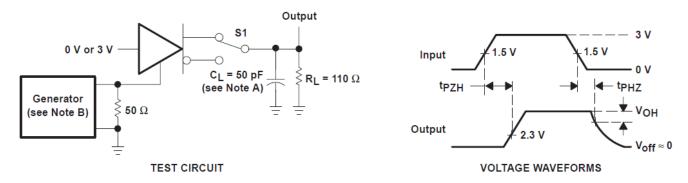


Figure 6-2. Driver V_{OD3}



- A. C_L includes probe and jig capacitance.
- B. The input pulse is supplied by a generator having the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, tr ≤ 6 ns, tf ≤ 6 ns, Z_O = 50 Ω.

Figure 6-3. Driver Test Circuit and Voltage Waveforms



A. C_L includes probe and jig capacitance.



B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, tr \leq 6 ns, tf \leq 6 ns, Z_O = 50 Ω .

Figure 6-4. Driver Test Circuit and Voltage Waveforms

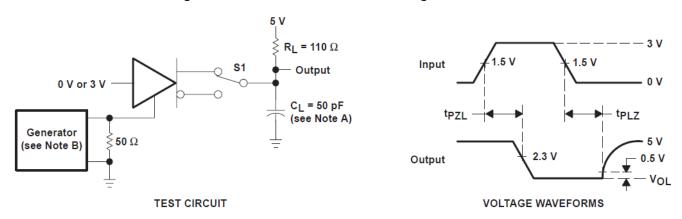


Figure 6-5. Driver Test Circuit and Voltage Waveforms

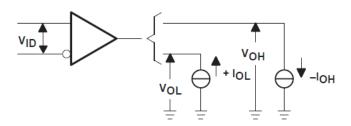
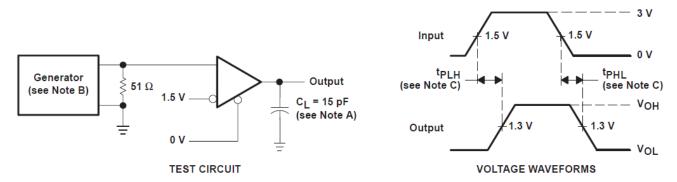


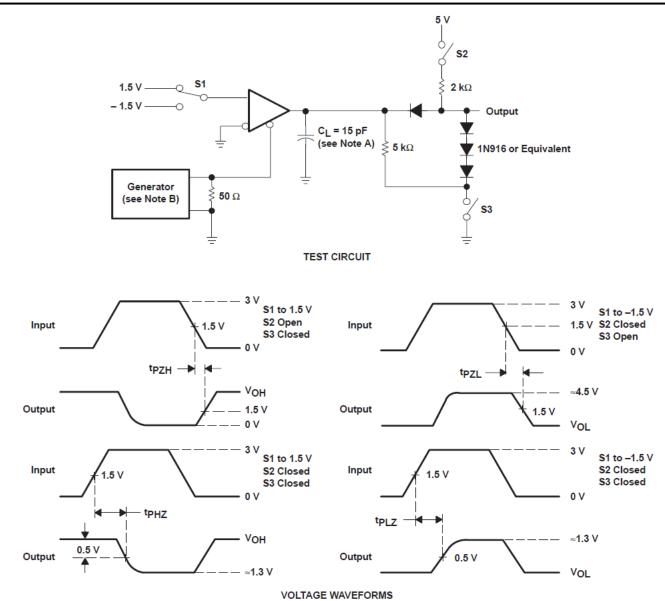
Figure 6-6. Receiver V_{OH} and V_{OL} Test Circuit



- A. C_L includes probe and jig capacitance.
- B. The input pulse is supplied by a generator having the following characteristics: PRR ≤ 1 MHz, 50% duty cycle, tr ≤ 6 ns, tf ≤ 6 ns, Z_O = 50 O
- C. $t_{pd} = t_{PLH}$ or t_{PHL} .

Figure 6-7. Receiver Test Circuit and Voltage Waveforms





- A. C_L includes probe and jig capacitance.
- B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, tr \leq 6 ns, tf \leq 6 ns, Z_O = 50 Ω .

Figure 6-8. Receiver Test Circuit and Voltage Waveforms



7 Detailed Description

7.1 Functional Block Diagram

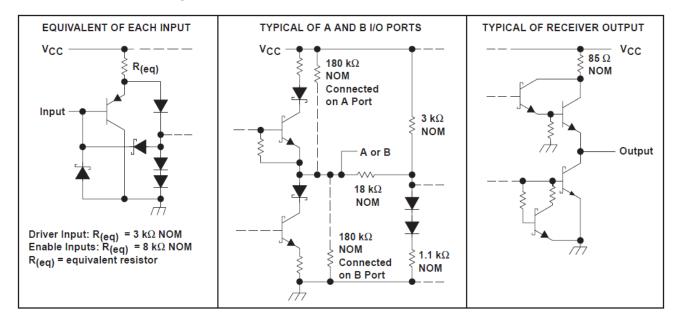


Figure 7-1. Schematic of Inputs and Outputs

7.2 Device Functional Modes

Function Tables

Table 7-1. Driver⁽¹⁾

INPUT	ENABLE	OUTPUTS					
D	DE	A	В				
Н	Н	Н	L				
L	Н	L	Н				
X	L	Z	Z				

(1) H = high level, L = low level, X = irrelevant, Z = high impedance

Table 7-2. Receiver⁽¹⁾

DIFFERENTIAL INPUTS A-B	ENABLE RE	OUTPUT R
V _{ID} ≥ 0.2 V	L	Н
-0.2 V < V _{ID} < 0.2 V	L	?
V _{ID} ≤ -0.2 V	L	L
X	Н	Z
Inputs open	L	Н

(1) H = high level, L = low level, X = irrelevant, Z = high impedance



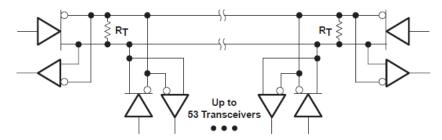
8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

8.2 Typical Application



A. The line should terminate at both ends in its characteristic impedance ($R_T = Z_0$). Stub lengths off the main line should be kept as short as possible.

Figure 8-1. Typical Application Circuit



9 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

9.1 Documentation Support

9.1.1 Related Documentation

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.4 Trademarks

TI E2E™ is a trademark of Texas Instruments.

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 30-Jul-2024

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN65ALS176DR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65A176	Samples
SN75ALS176AD	ACTIVE	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	7A176A	Samples
SN75ALS176ADR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	7A176A	Samples
SN75ALS176ADRG4	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	7A176A	Samples
SN75ALS176AP	ACTIVE	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	75ALS176A	Samples
SN75ALS176BD	OBSOLETE	SOIC	D	8		TBD	Call TI	Call TI	0 to 70	7A176B	
SN75ALS176BDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	(75A176, 7A176B)	Samples
SN75ALS176BP	ACTIVE	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	75ALS176B	Samples
SN75ALS176D	OBSOLETE	SOIC	D	8		TBD	Call TI	Call TI	0 to 70	75A176	
SN75ALS176P	ACTIVE	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	75ALS176	Samples
SN75ALS176PE4	ACTIVE	PDIP	Р	8	50	RoHS & Green	NIPDAU	N / A for Pkg Type	0 to 70	75ALS176	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



PACKAGE OPTION ADDENDUM

www.ti.com 30-Jul-2024

- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE MATERIALS INFORMATION

www.ti.com 25-Sep-2024

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65ALS176DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
SN75ALS176ADR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
SN75ALS176BDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1



www.ti.com 25-Sep-2024



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65ALS176DR	SOIC	D	8	2500	356.0	356.0	35.0
SN75ALS176ADR	SOIC	D	8	2500	353.0	353.0	32.0
SN75ALS176BDR	SOIC	D	8	2500	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

www.ti.com 25-Sep-2024

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN75ALS176AD	D	SOIC	8	75	507	8	3940	4.32
SN75ALS176AP	Р	PDIP	8	50	506	13.97	11230	4.32
SN75ALS176BP	Р	PDIP	8	50	506	13.97	11230	4.32
SN75ALS176P	Р	PDIP	8	50	506	13.97	11230	4.32
SN75ALS176PE4	Р	PDIP	8	50	506	13.97	11230	4.32



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



P (R-PDIP-T8)

PLASTIC DUAL-IN-LINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001 variation BA.



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